

2025 JOINT WORKSHOP OF FKPPN AND FJPPN
14-16 MAY 2025



Romain Gaïor

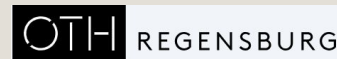
LPNHE

2025/05/15

TYL/FJPPN workshop
Nantes



K. Martens
M. Yamashita
C. Ishikawa
X. Wang



Prof R. Schreiner
M. Hausladen



Prof C. Weinheimer

Fea In XE Detector

Scientific context

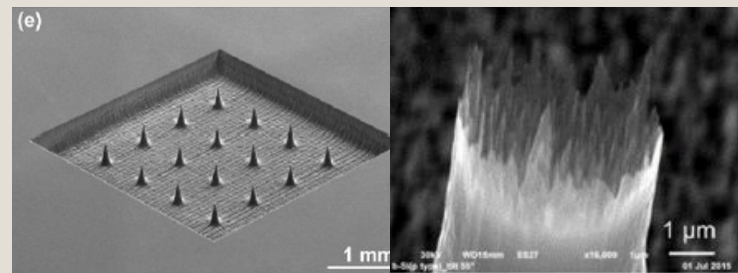
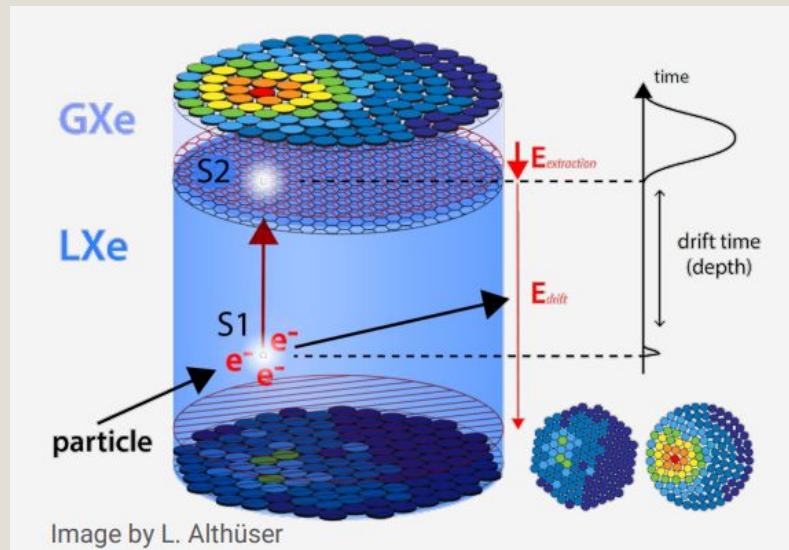
XLZD: Next generation LXe Experiment (50-100 tons) for **rare event searches** (Dark Matter, neutrinos, $0\nu\text{BB}$)

(some) Problematics with large detectors

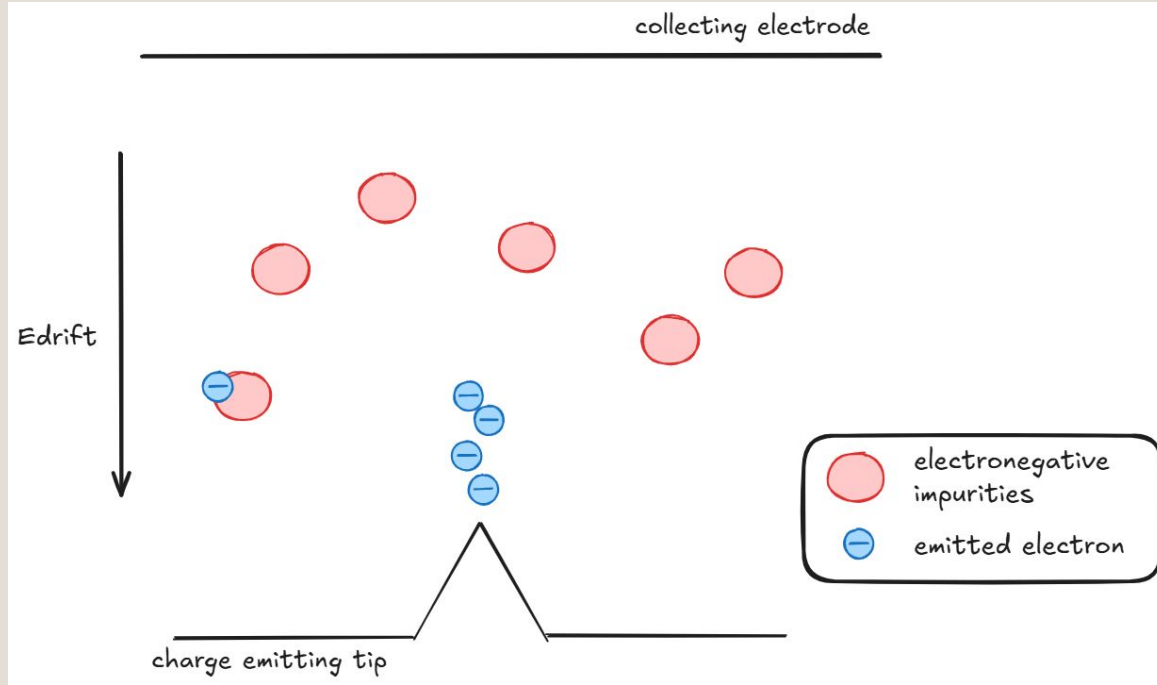
- Radioactive purity: need for faster **purification** methods (Radon)
- Electrodes for **2nd scintillation**:
Mechanical issues, resolution, spurious charge

FEA: Microscopic Conductive structure

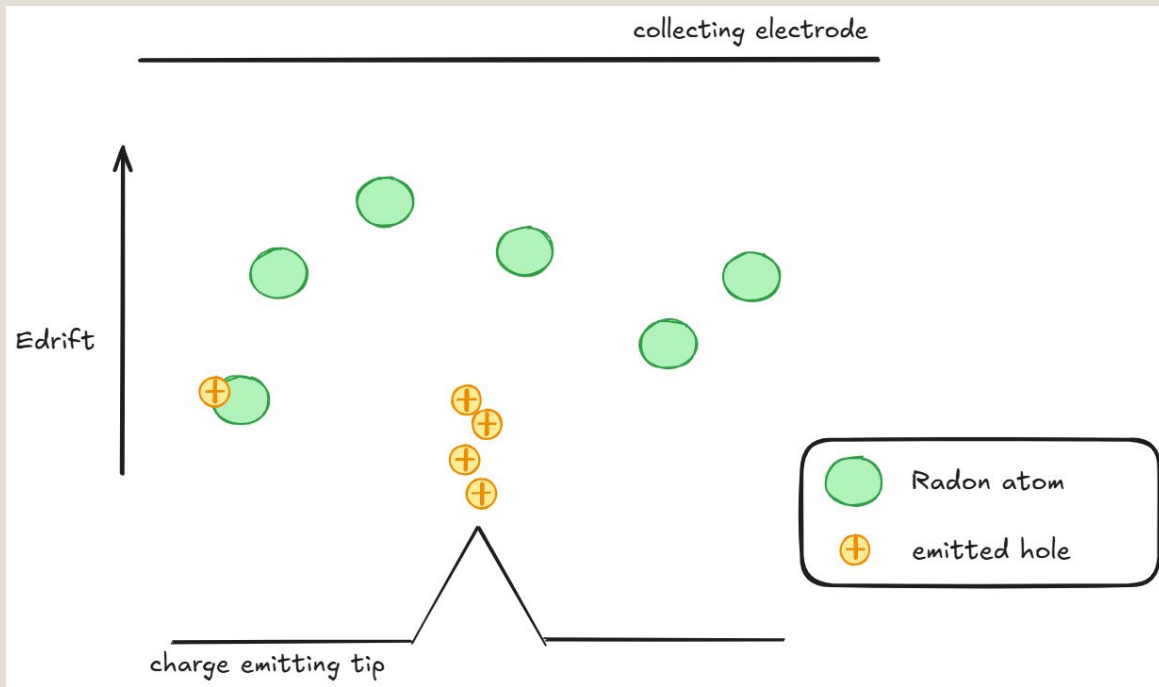
- **Large electric field** site
- Various shape / material (Cu, Si) / fabrication method
- Used in industry in vacuum



PURIFICATION

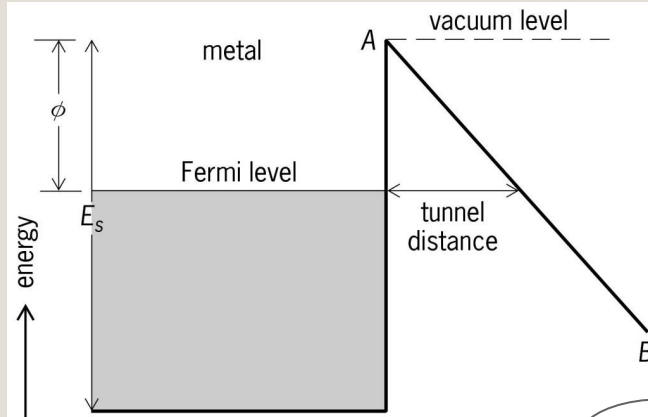


PURIFICATION



Field effect charge emission

Fowler-Nordheim tunneling (~1930)



$\sim 10^9 \text{V/m}$

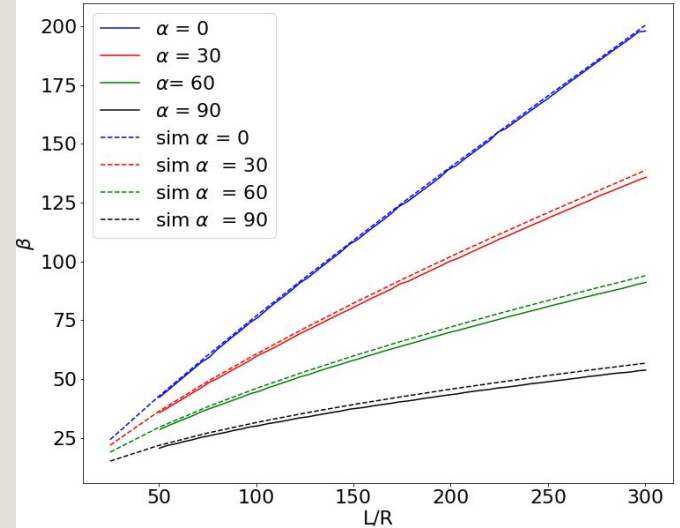
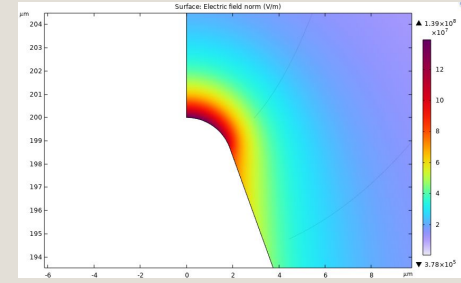
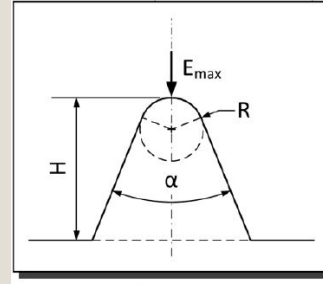
$$j = \frac{q^3}{2\pi h} \cdot \frac{\sqrt{\mu}}{(\phi + \mu) \sqrt{\phi}} \cdot F_l^2 \exp\left(-\frac{4\kappa\phi^{3/2}}{3qF_l}\right)$$

F_l = Electric surface field

Very high local field required

Field enhancement β

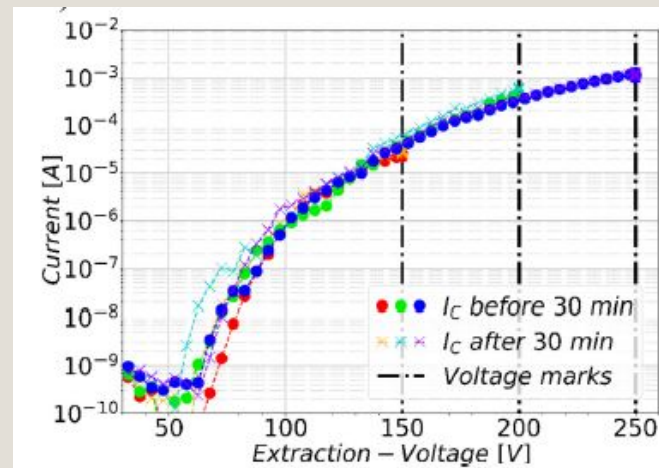
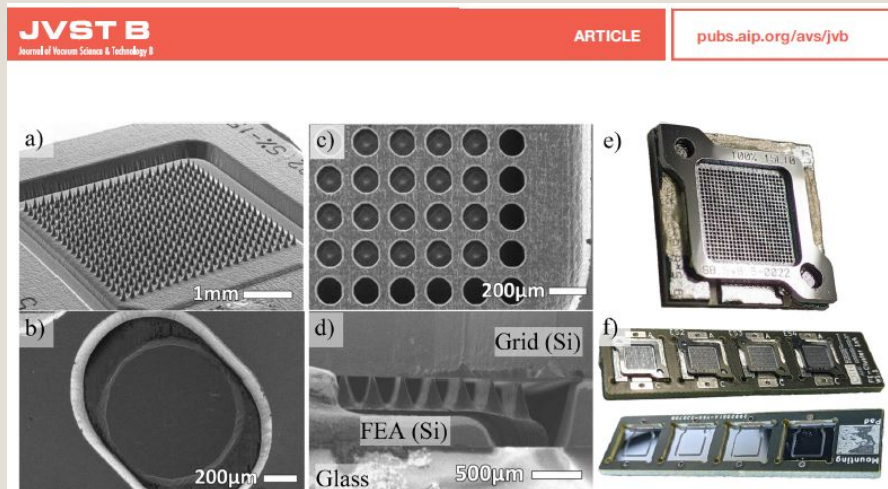
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S.Podenok, M.Sveningsson, K.Hansen, E.Campbell, "Electric field enhancement factor around a metallic, end-capped cylinder", NANO1(1), S.87-93(2006).

Charge emission in vacuum

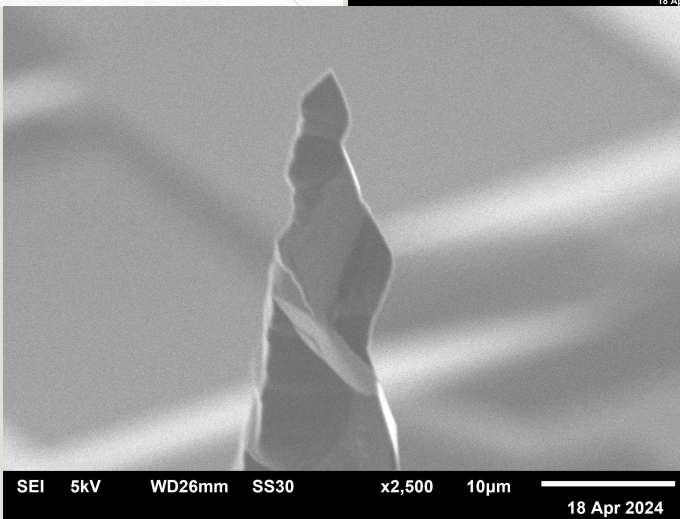
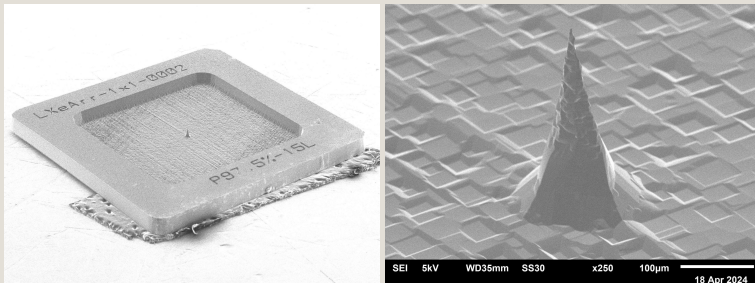
Result from OTH in Vacuum Hausladen *et al.* DOI: [10.1116/6.0003233](https://doi.org/10.1116/6.0003233)



- Silicon laser micromachined tip array of 21x21
- Onset current of ~70V
- Stable current obtained
- Current distributed evenly over the array

Single tip in LXe

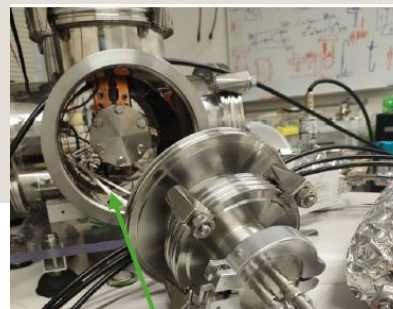
Tip for LXe tests



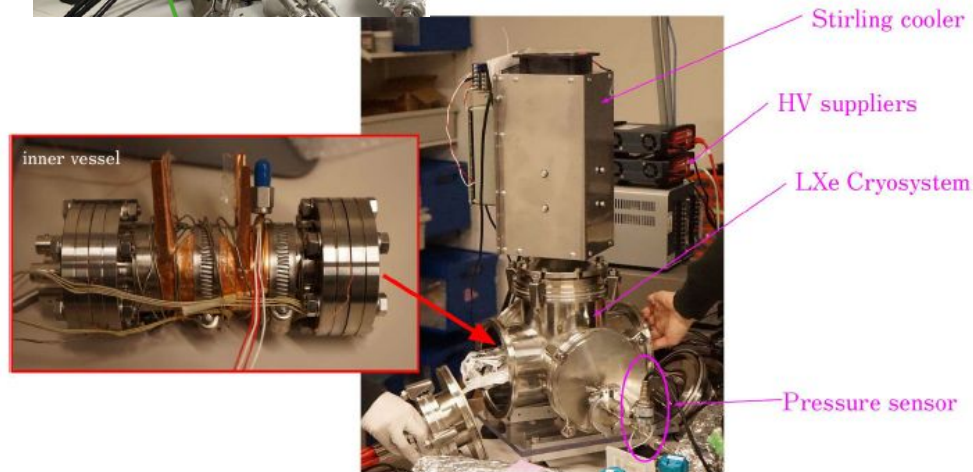
- We took first measurement in 2023 with a 21x21 array
→ Emission but hard to interpret
- Going back to 1 single tip
- First “conditioning” in vacuum
→ smoothens the surface

Single tip in LXe

Inner vessel

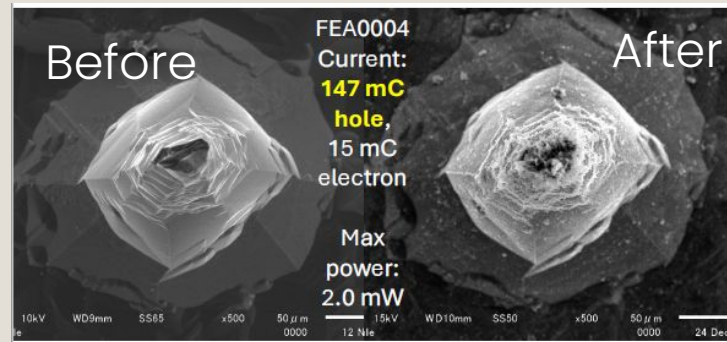
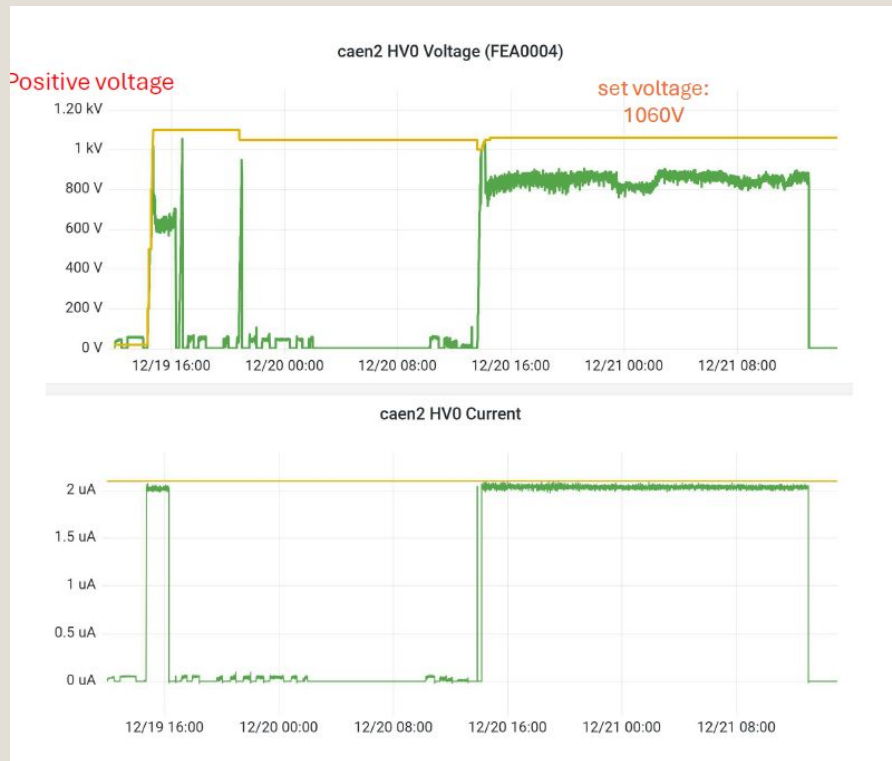


Cryogenic Setup



Results

Electron AND Hole emission observed !



- Established procedure to obtain stable emission
- Change of tip structure observed to be understood
- Effect of coating ?

Plans

- Experience building up on the tip conditioning
- Work on simulations is ongoing
- Distribute emission over an array
- Measure attachment to radon with a dedicated experiment →

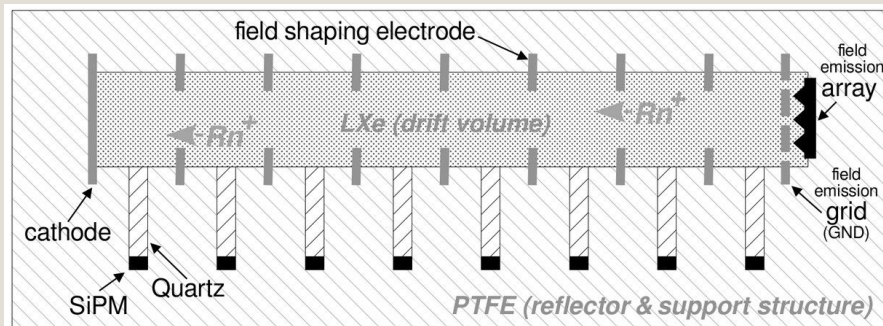
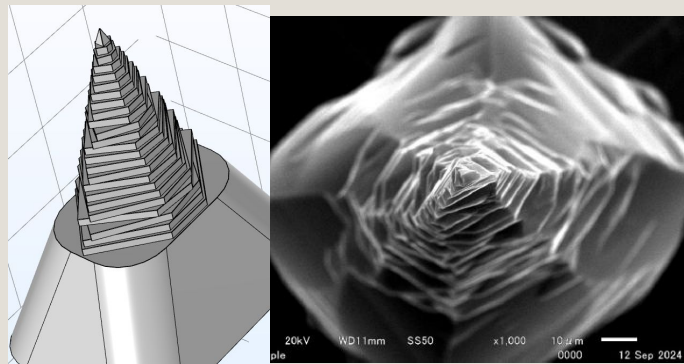
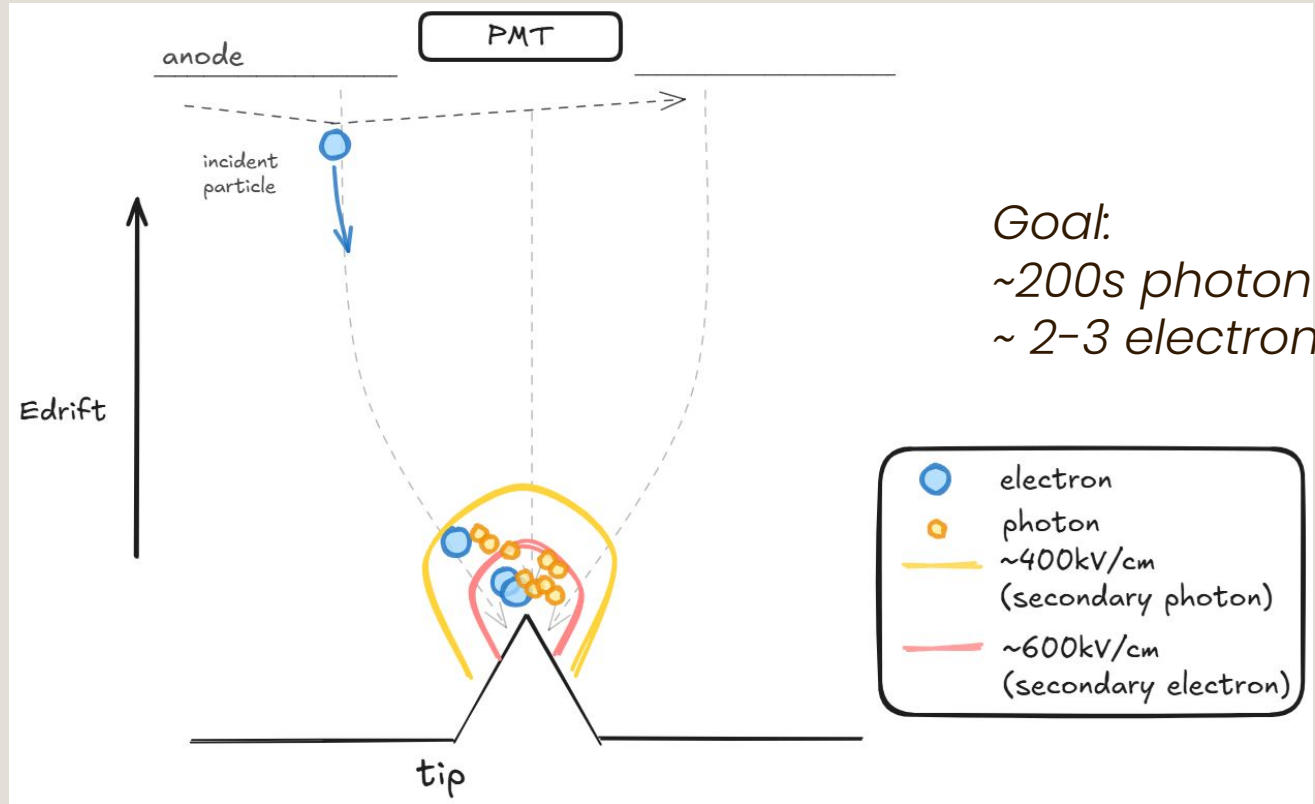


Fig. 1 Schematic of LXe drift volume

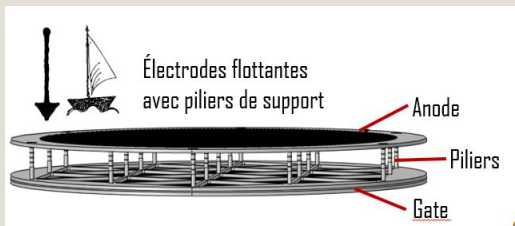
K. Martens credit

Secondary scintillation



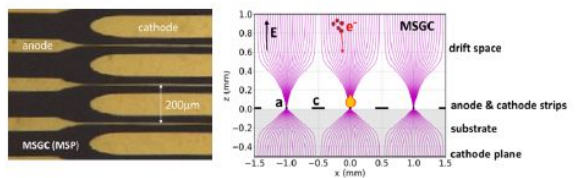
Electrode R&Ds

Double phase "Floating electrodes"



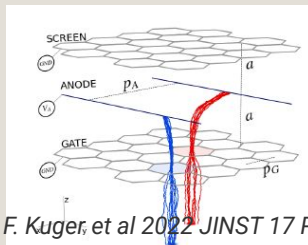
Xe-Lab

Single phase Microstrips

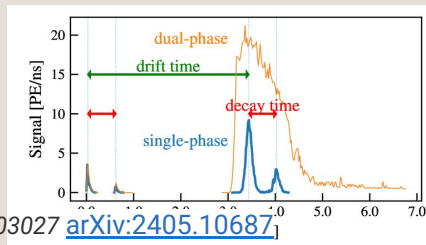


G. Martinez-Lema et al 2024 JINST 19 P02037

Single phase with wire

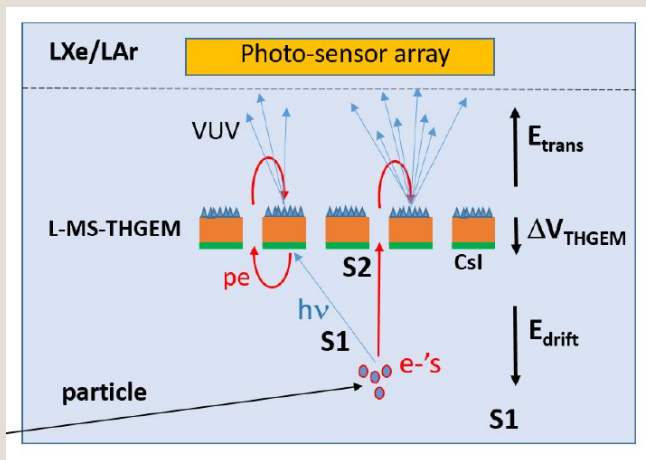


F. Kuger, et al 2022 JINST 17 P03027



[arXiv:2405.10687](https://arxiv.org/abs/2405.10687)

Single phase with micro/nano structure



A. Breskin 2022 JINST 17 P08002 / arXiv:2203.01774

- **No liquid - gas interface**
- **No electrode sagging**
- **No delayed electrons**
- **Cleaner S2 signal**
- **Large local electric field**
- **Not as studied as double phase for rare event searches**

Secondary scintillation simulation

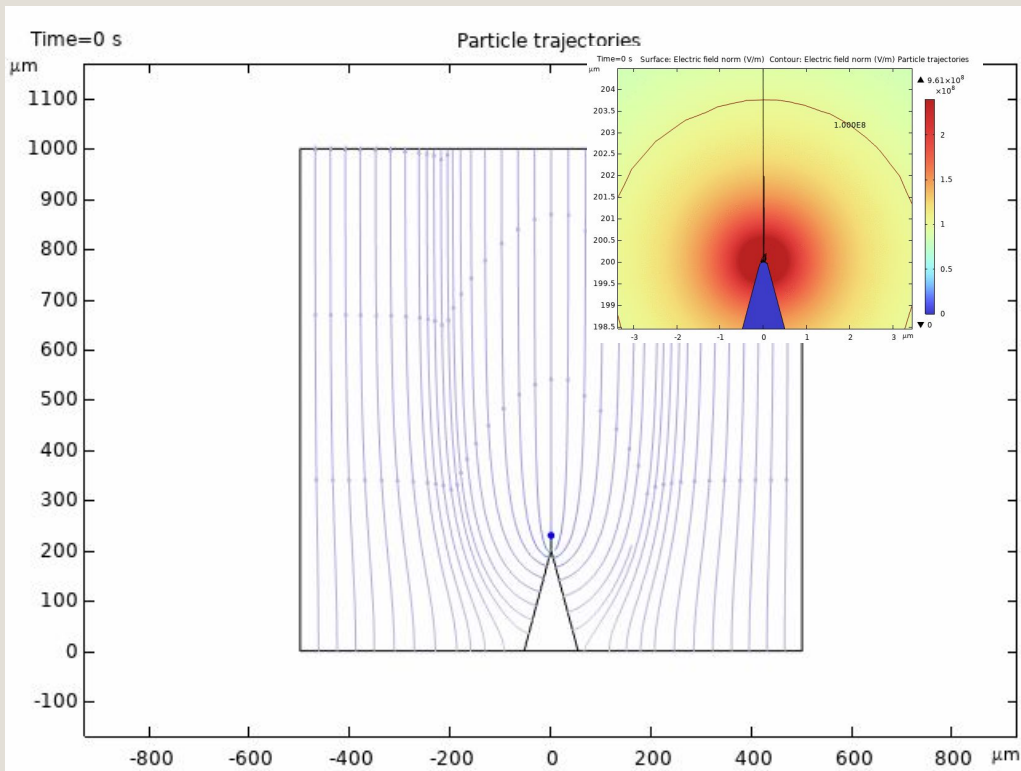
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INTRO

CHARGE EMISSION

SECONDARY
SCINTILLATION

CONCLUSION



1. E-field simulation
2. Electron tracking
3. Emission simulation

$$\Delta N_e = N_e \theta_0 \exp \left(-\frac{\theta_1}{E(\vec{x}, V_A, d_w) - \theta_2} \right) \Delta \vec{x},$$
$$\Delta N_\gamma = N_e \theta_3 (E(\vec{x}, V_A, d_w) - \theta_4) \Delta \vec{x},$$

$$\theta_2 = 400 \text{ kV/cm}$$

$$\theta_4 = 600 \text{ kV/cm}$$

arXiv:1408.6206v3 / E Aprile et al 2014 JINST 9 P11012

→ Started with full COMSOL

→ Now Emission with python code

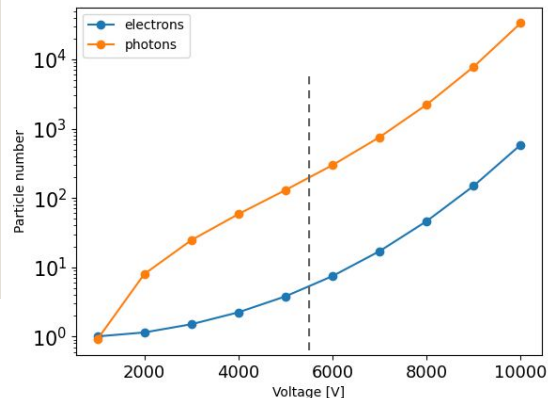
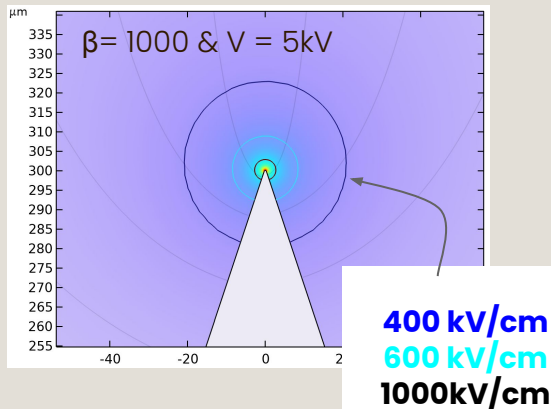
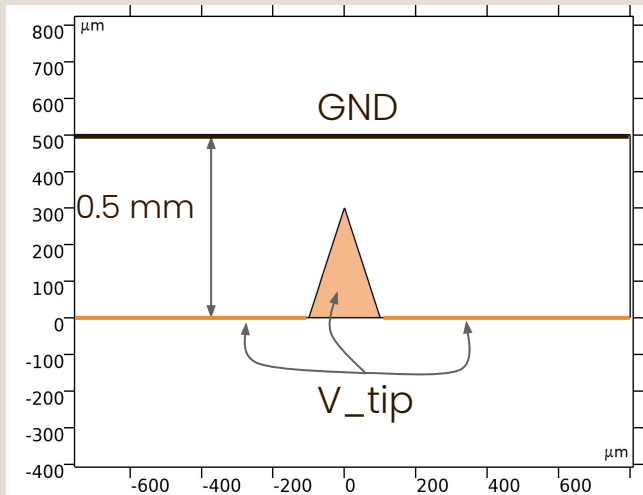
Simple geometry

INTRO

CHARGE EMISSION

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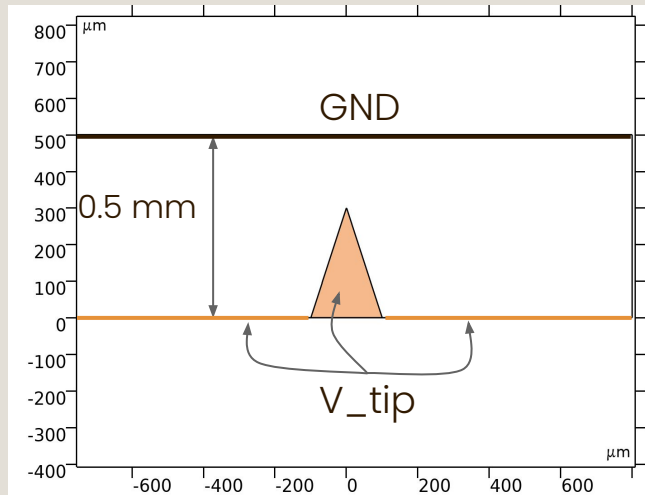
- Number of electron vs photon
- Charge emission ?

→ Need a smaller enhancement factor

Simple geometry

INTRO

CHARGE EMISSION

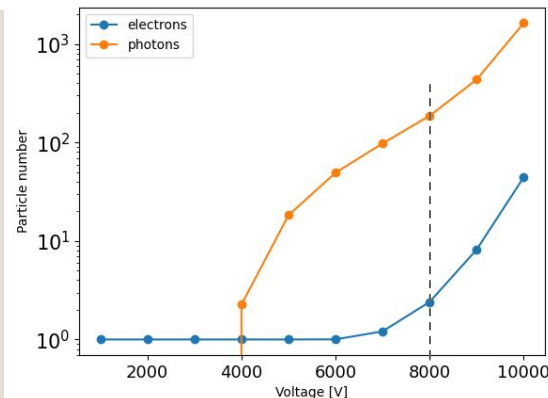
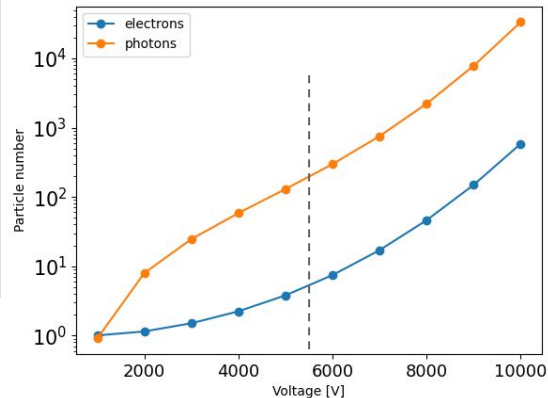
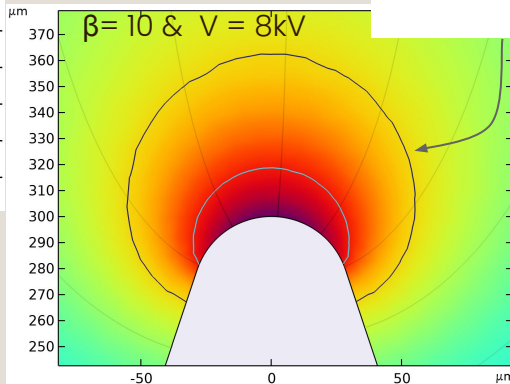
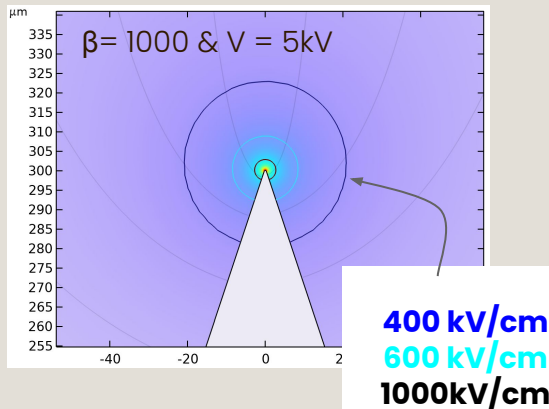


SECONDARY SCINTILLATION

CONCLUSION

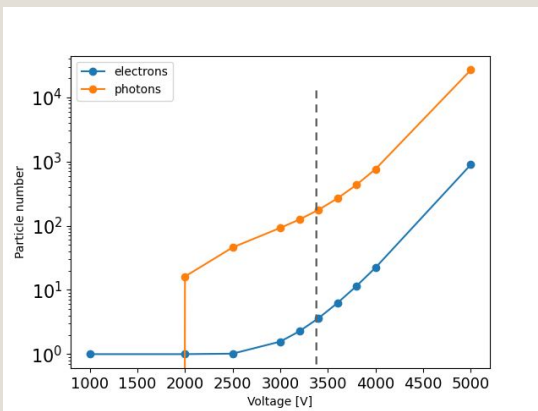
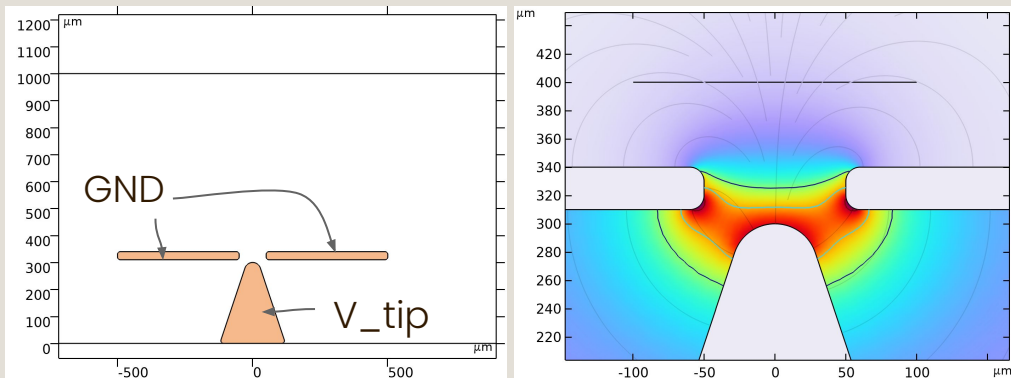
- Number of electron vs photon
- Charge emission ?

→ Need a smaller enhancement factor



Many possibilities

Gated FEA



Many possibilities

Gated FEA

Various geometry

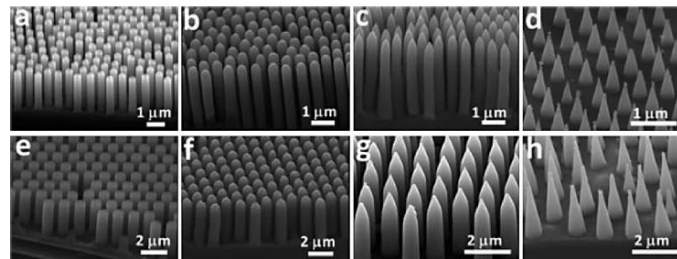
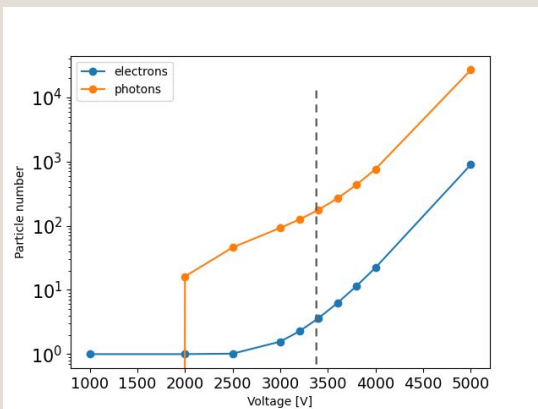
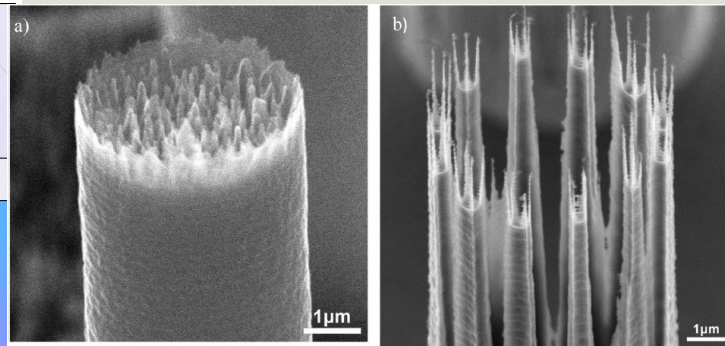
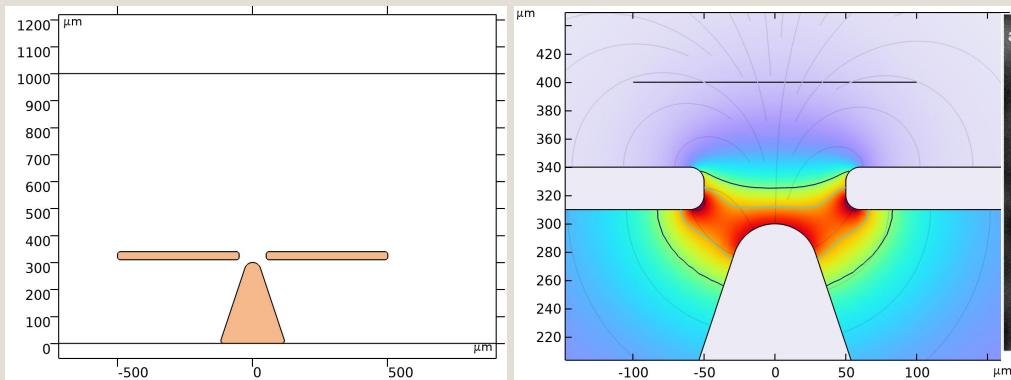
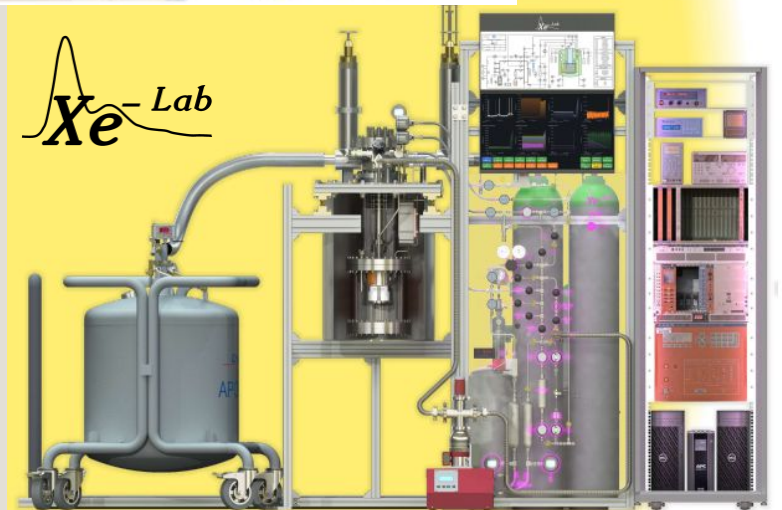
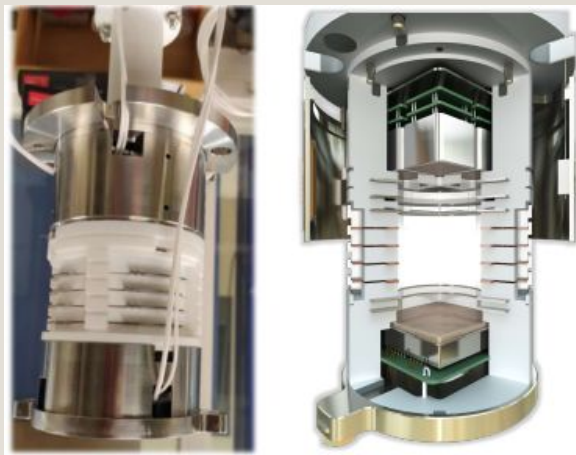


Figure 14. SEM images of highly regular (a and e) nanopillar, (b and f) nanorod, (c and g) nanopencil, and (d and h) nanocone Si arrays, produced by wet-etching. (Reproduced from ref. [81] with permission from the authors and the Royal Society of Chemistry).

Plans

- Explore / optimize geometries with simulation
 - among existing ones
 - discuss feasibility if not existing
- Test simulation with experiment
 - Xelab@LPNHE is now an option
- Measure performance of these structures



Budget request

- **1 trip France → Japan:**
 - Work on the charge emission setup
 - Acquire experience on tip conditioning
- **1 trip Japan → France:**
 - Work on the secondary scintillation setup
 - Profit of the Xelab facility

THANK YOU !

